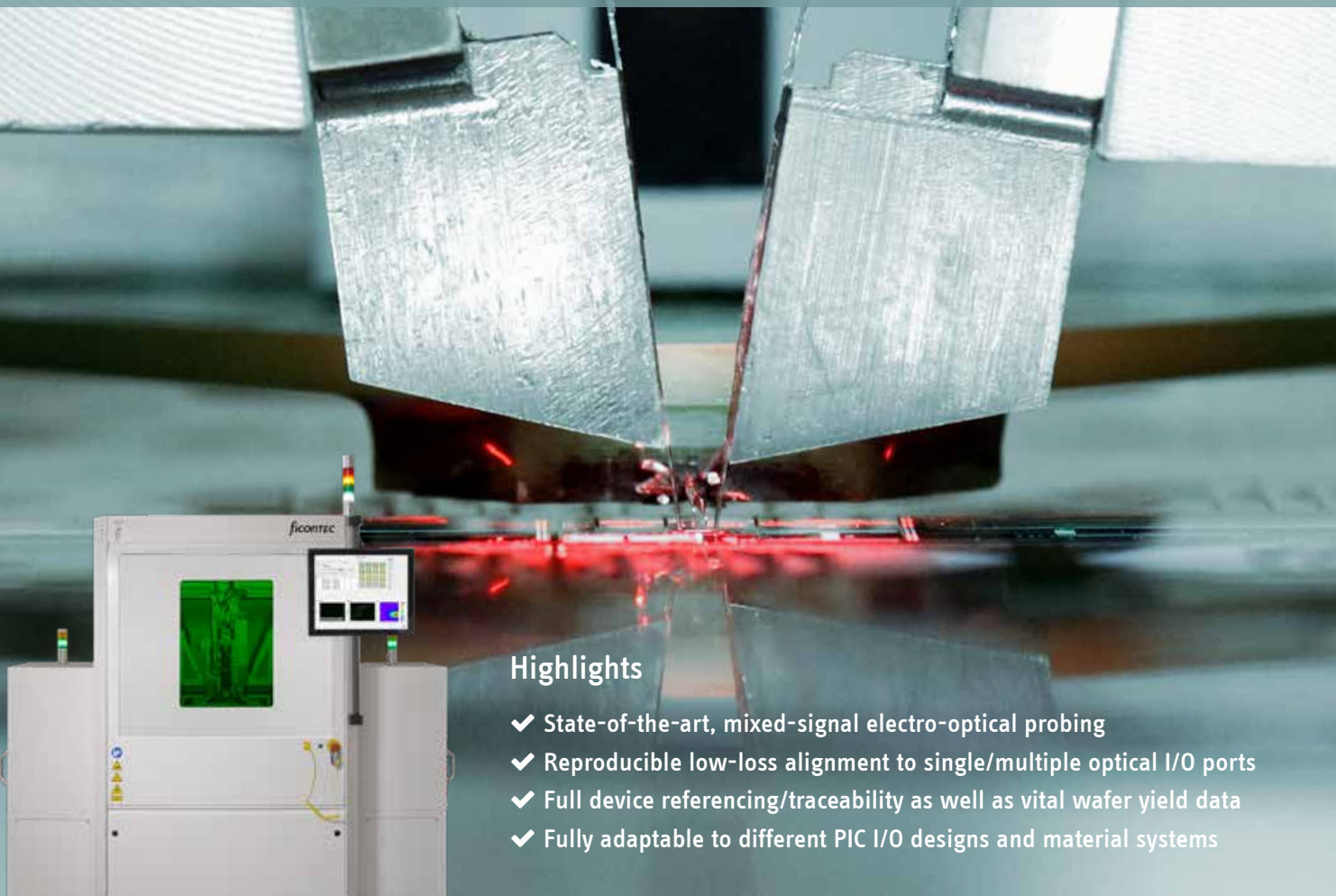




# WAFER TESTLINE

## Wafer-level photonic device test

Innovative mixed-signal electro-optical test systems for non-singulated photonic integrated circuits (PICs) and other optoelectronic devices. Featuring fully automated DC, RF and optical measurements both on-wafer and for single photonic devices on appropriate carrier formats.



### Highlights

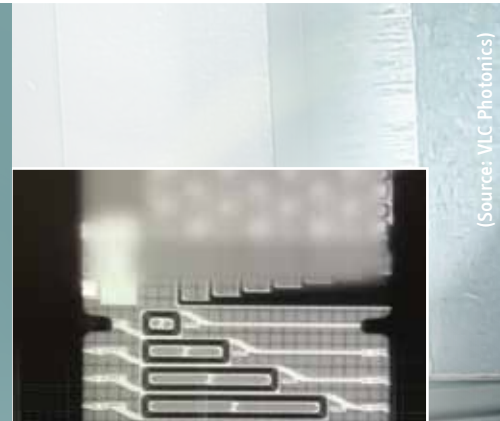
- ✓ State-of-the-art, mixed-signal electro-optical probing
- ✓ Reproducible low-loss alignment to single/multiple optical I/O ports
- ✓ Full device referencing/traceability as well as vital wafer yield data
- ✓ Fully adaptable to different PIC I/O designs and material systems

## Fully automated electro-optical test of wafer-level devices

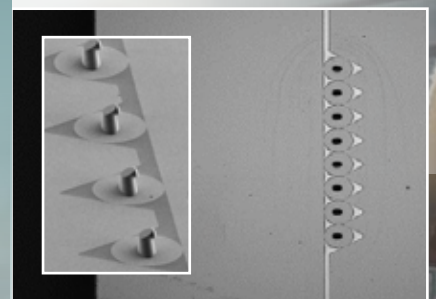
ficonTEC's WAFFER TESTLINE product line is specially designed as a versatile electro-optical test-&-measurement system platform for wafer-level photonic device test, but also work equally well for multiple singulated devices on appropriate carrier formats.

For R&D proof-of-concept device test tasks, WAFFER TESTLINE provides state-of-the-art, multi-channel e/o test of on-wafer waveguide and PIC I/O. Custom 3D-printed fiber tips provide support for edge-coupling, so low-loss coupling is enabled for all optical coupling mechanisms. A re-configurable probe-wafer layout even caters to multiple PIC designs on a multi-project wafer (MPW).

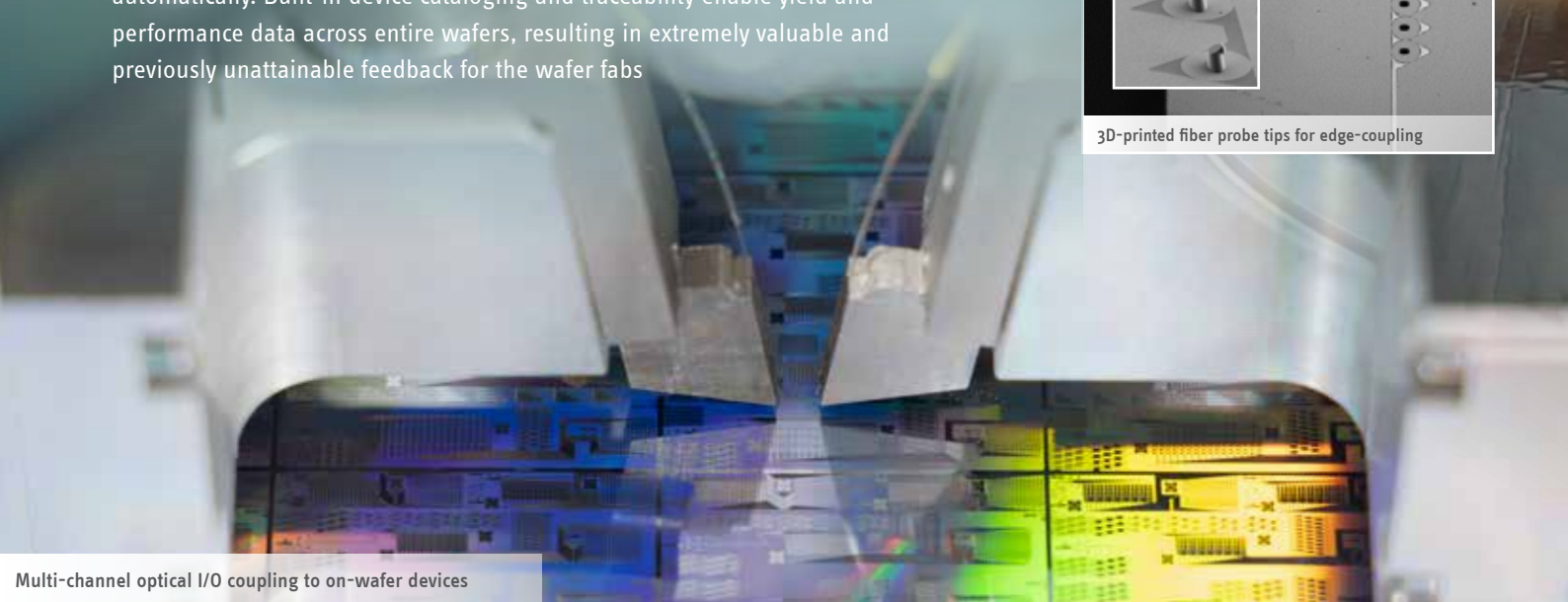
For volume manufacturing, all identical devices on a wafer can be tested fully automatically. Built-in device cataloging and traceability enable yield and performance data across entire wafers, resulting in extremely valuable and previously unattainable feedback for the wafer fabs



I/O optical channel recognition via machine vision



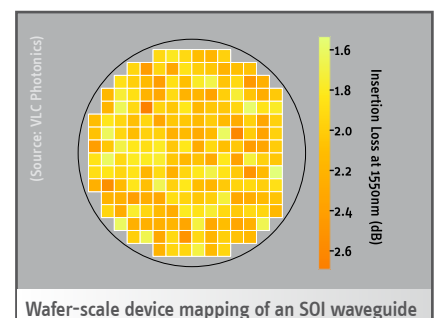
3D-printed fiber probe tips for edge-coupling



Multi-channel optical I/O coupling to on-wafer devices

## Software control

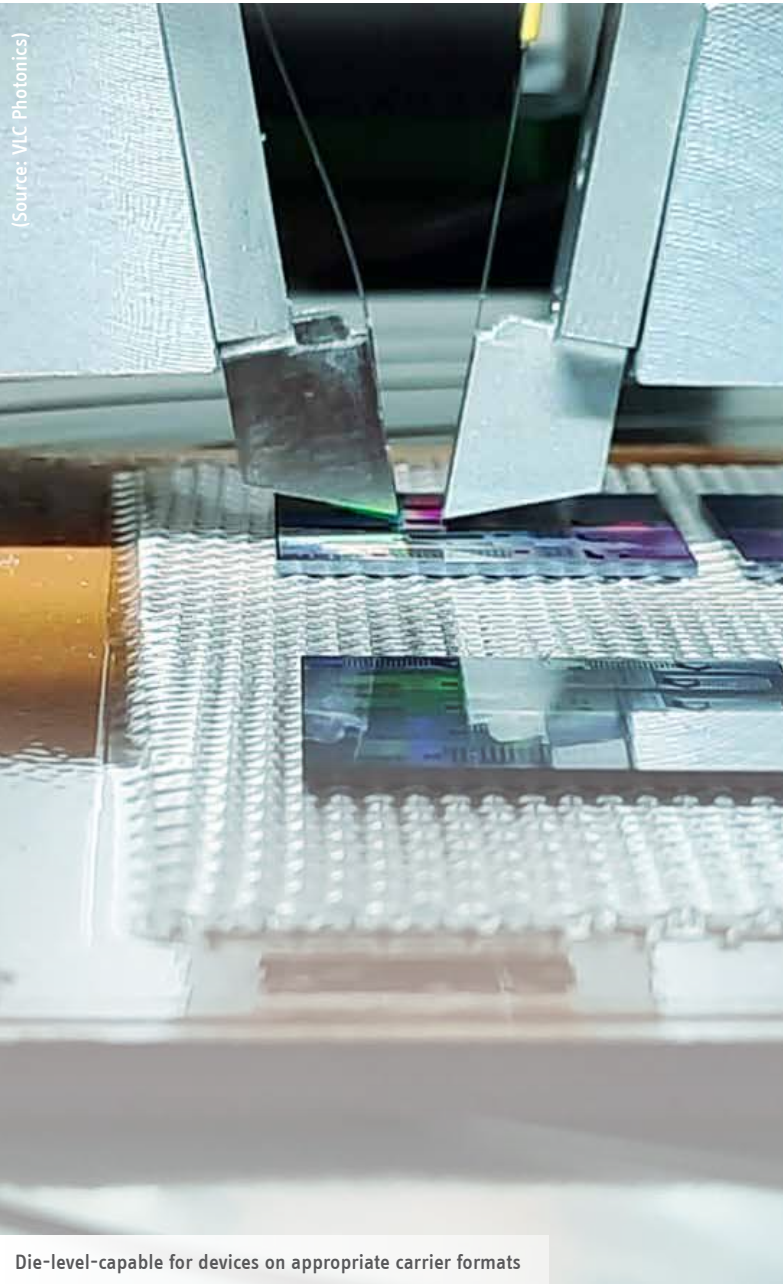
PCM is ficonTEC's unified process-oriented control interface that ships with all turn-key stand-alone systems and multiple machine configurations. PCM features an intuitive UI and an up-to-date feature set that includes all machine vision, high-resolution positioning, system management software and test routines required to reliably and repeatably drive passive/active alignment and bonding process hardware.





# WAFER TESTLINE

Wafer-level photonic device test



(Source: VLC Photonics)



## Key features

- Automated I/O port referencing to sub- $\mu\text{m}$  accuracy
- Vertical and edge alignment to I/O ports in max. 4s
- Low-loss I/O port coupling with  $< 0.4$  dB repeatability
- MPW-capable due to adaptable probe-wafer layout
- Wafer fabs receive PIC yield data across entire wafer

## General tasks & applications

- Automated test-&-qualify for passive/active devices
- Proof-of-concept and low-complexity volume e/o test
- FTTX transceivers, MOEMS and sensor assemblies
- Camera modules, 3D scanning & lidar, PICs & silicon photonics
- Configurable for high-complexity copackaged applications

Die-level-capable for devices on appropriate carrier formats

## Modular & (re-)configurable

- State-of-the-art 4" to 12" wafer handling options
- Optional modules expand operational functionality
- Flexibly scalable to suit needs 'From Lab to Fab'
- Add and/or swap modules to re-configure & re-purpose



## MANUFACTURING MADE LIGHT

Solutions for integrated photonics. Built to scale.

ficonTEC is the global market leader for automated assembly and test solutions for modern optoelectronics and integrated photonic devices. In serving development and manufacturing needs for telecom/datacom interconnects, sensors & lidar, camera modules, high-power diode lasers and many other integrated applications for over 20 years, ficonTEC's suite of process capabilities is unmatched.

Additionally, a unique and modular approach to production equipment design means that each solution is the automated and optimized embodiment of a customer-defined process.

### Contact us





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US and Far East as well as for  
distributors around the globe:

[www.ficontec.com/locations](http://www.ficontec.com/locations)



Core system specifications	 WT800	 WT1200	 WT1600	 WT2000
Motion system	single optical probing with 6-axis high-precision alignment* electrical probing with 3-axis alignment		multiple optical probing with 6-axis high-precision alignment* electrical probing with 3-axis alignment	
Wafer table	up to 4" wafers (+/- 100° rotation only)		up to 12" wafers (+/- 100° rotation + xy translation)	
Temperature control	temperature-controlled chuck, +15 to +80 (+/- 0.1) °C			
Handling options (wafer)	manual loading		manual loading or wafer feed system	
Handling options (die)	manual loading		automated loading	
Machine vision	system referencing and observation camera options   device and I/O port referencing			
Software features	flexible and powerful process programming   extended operator-less control   Windows 10 PC			
Minimum connections	120 VAC (or country specific)   air/vacuum   100 Mbit/s network			
Cleanroom compliance	ISO 6**			
Physical features	rugged steel base production cell			
Dimensions (w x b x h, mm)	800 x 1200 x 1600/2000	1200 x 1200 x 2000	1600 x 1200 x 2000	1800 x 1200 x 2000
Weight (typ., kg)	1300	1800	2300	2500

\* alternative multi-axis configurations optional \*\* others available on request

- All ficonTEC systems are compatible with PXI-based electro-optical instrumentation modules and leveraging of NI's LabVIEW™. Non-LabVIEW and alternative instrumentation environments are also compatible.
- In addition to all driving align-&-attach processes, PCM software also includes AI-based Deep Learning defect recognition capability, optional ML-oriented production data monitoring, and can direct call functions in Python files.
- Special purpose cells, robotic systems as well as some TESTLINE functionality can be flexibly incorporated to suit customer needs.